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INFORMATION DISCLOSURE STATEMENT BY APPLICANT				SNDK.256US0		10/052,924	
				Applicant(s)			
(Use several sheets if necessary)				Mokhlesi et al.			
Filing Date				January 18, 2002		Group	
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
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							Translation	
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
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	12	Bloom, et al., "1/f Noise Reduction of Metal-Oxide-Semiconductor Transistors by Cycling from Inversion to Accumulation," <i>Appl. Phys. Lett.</i> 58 (15), 15 April 1991, pp. 1664-1666.
	13	Dierickx et al., "The Decrease of "Random Telegraph Signal" Noise in Metal-Oxide-Semiconductor Field-Effect Transistors When Cycled from Inversion to Accumulation," <i>J. Appl. Phys.</i> 71 (4), 15 February 1992.
	14	Hung et al., "Random Telegraph Noise of Deep-Submicrometer MOSFET's," <i>IEEE Electron Device Letters</i> , Vol. 11, No. 2, February 1990, pp. 90-92.
HU	15	Hung et al., "A Unified Model for the Flicker Noise in Metal-Oxide-Semiconductor Field-Effect Transistors," <i>IEEE Transactions on Electron Devices</i> , Vol. 37, No. 3, March 1990, pp. 654-665.